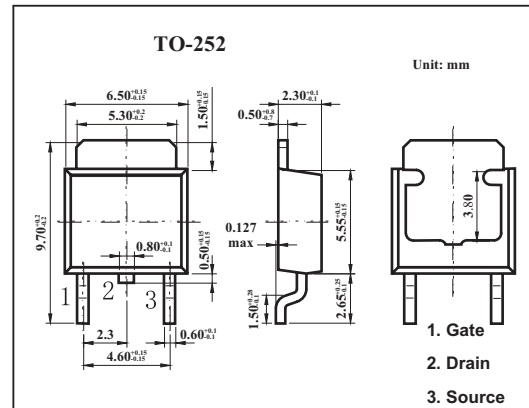
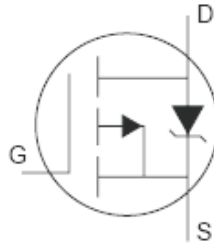


HEXFET[®] Power MOSFET

KRFR6215

■ Features

- Advanced Process Technology
- Surface Mount
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated



■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Continuous Drain Current, $V_{GS} @ 10V, T_c = 25^\circ\text{C}$	I_D	-13	A
Continuous Drain Current, $V_{GS} @ 10V, T_c = 100^\circ\text{C}$	I_D	-9	
Pulsed Drain Current*1	I_{DM}	-44	
Power Dissipation $T_C = 25^\circ\text{C}$	P_D	110	W
Linear Derating Factor		0.71	W/°C
Gate-to-Source Voltage	V_{GS}	± 20	V
Single Pulse Avalanche Energy*3	E_{AS}	310	mJ
Avalanche Current *1	I_{AR}	-6.6	A
Repetitive Avalanche Energy	E_{AR}	11	mJ
Peak Diode Recovery dv/dt *2	dv/dt	5	V/ns
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 to + 175	°C
Junction-to-Case	$R_{\theta JC}$	1.4	°C/W
Junction-to-Ambient	$R_{\theta JA}$	50	°C/W
Junction-to-Ambient	$R_{\theta JA}$	110	°C/W

*1 Repetitive rating; pulse width limited by max. junction temperature.

*2 $I_{SD} \leq -6.6A$, $di/dt \leq -620A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 175^\circ\text{C}$

*3 Starting $T_J = 25^\circ\text{C}$, $L = 14mH$, $R_G = 25\Omega$, $I_{AS} = -6.6A$.

KRFR6215

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250 \mu A$	-150			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(BR)DSS}/\Delta T_J$	$I_D = -1mA, \text{Reference to } 25^\circ C$		-0.02		V/°C
Static Drain-to-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = -10V, I_D = -6.6A^*1$			0.295	Ω
		$V_{GS} = -10V, I_D = -6.6A, T_J = 150^\circ C^*1$			0.58	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250 \mu A$	-2.0		-4.0	V
Forward Transconductance	g_{fs}	$V_{DS} = -50V, I_D = -6.6A^*1$	3.6			S
Drain-to-Source Leakage Current	I_{DSS}	$V_{DS} = -150V, V_{GS} = 0V$			-25	μA
		$V_{DS} = -120V, V_{GS} = 0V, T_J = 150^\circ C$			-250	
Gate-to-Source Forward Leakage	I_{GSS}	$V_{GS} = 20V$			100	nA
Gate-to-Source Reverse Leakage		$V_{GS} = -20V$			-100	
Total Gate Charge	Q_g	$I_D = -6.6A$			66	nC
Gate-to-Source Charge	Q_{gs}	$V_{DS} = -120V$			8.1	
Gate-to-Drain ("Miller") Charge	Q_{gd}	$V_{GS} = -10V, ^*1$			35	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -75V$		14		ns
Rise Time	t_r	$I_D = -6.6A$		36		
Turn-Off Delay Time	$t_{d(off)}$	$R_G = 6.8 \Omega$		53		
Fall Time	t_f	$R_D = 12 \Omega ^*1$		37		
Internal Drain Inductance	L_D	Between lead, 6mm (0.25in.) from package and center of die contact		4.5		nH
Internal Source Inductance	L_S			7.5		nH
Input Capacitance	C_{iss}	$V_{GS} = 0V$		860		pF
Output Capacitance	C_{oss}	$V_{DS} = -25V$		220		
Reverse Transfer Capacitance	C_{rss}	$f = 1.0MHz$		130		
Continuous Source Current (Body Diode)	I_S	MOSFET symbol showing the integral reverse p-n junction diode.			-13	A
Pulsed Source Current (Body Diode) *2	I_{SM}				-44	
Diode Forward Voltage	V_{SD}	$T_J = 25^\circ C, I_S = -6.6A, V_{GS} = 0V^*1$			-1.6	V
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ C, I_F = -6.6A$		160	240	ns
Reverse Recovery Charge	Q_{rr}	$di/dt = 100A/\mu s^*1$		1.2	1.7	nC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

*1 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.

*2 Repetitive rating; pulse width limited by max